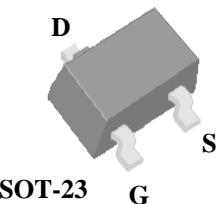


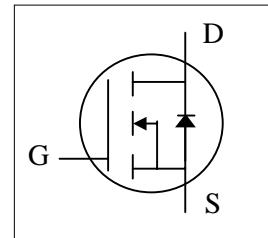


**N-CHANNEL ENHANCEMENT MODE  
POWER MOSFET**

- ▼ Capable of 1.8V Gate Drive
- ▼ Lower On-resistance
- ▼ Surface Mount Package
- ▼ RoHS Compliant



$BV_{DSS}$	30V
$R_{DS(ON)}$	35mΩ
$I_D$	5A



### Description

Xsemi MOSFETs utilized advanced processing techniques to achieve the lowest possible on-resistance, extremely efficient and cost-effectiveness device.

The SOT-23 package is widely used for all commercial-industrial applications.

### Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 8$	V
$I_D @ T_A=25^\circ\text{C}$	Drain Current <sup>3</sup> , $V_{GS} @ 4.5\text{V}$	5	A
$I_D @ T_A=70^\circ\text{C}$	Drain Current <sup>3</sup> , $V_{GS} @ 4.5\text{V}$	4	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	20	A
$P_D @ T_A=25^\circ\text{C}$	Total Power Dissipation	1.38	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

### Thermal Data

Symbol	Parameter	Value	Unit
$R_{thj-a}$	Maximum Thermal Resistance Junction-ambient <sup>3</sup>	90	°C/W

### Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=250\mu\text{A}$	30	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=4.5\text{V}$ , $I_{\text{D}}=5\text{A}$	-	-	35	$\text{m}\Omega$
		$V_{\text{GS}}=2.5\text{V}$ , $I_{\text{D}}=2.6\text{A}$	-	-	50	$\text{m}\Omega$
		$V_{\text{GS}}=1.8\text{V}$ , $I_{\text{D}}=1.0\text{A}$	-	-	80	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_{\text{D}}=250\mu\text{A}$	0.3	-	1.2	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=5\text{V}$ , $I_{\text{D}}=5\text{A}$	-	9	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=24\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	10	$\text{uA}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}= \pm 8\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_{\text{g}}$	Total Gate Charge <sup>2</sup>	$I_{\text{D}}=5\text{A}$	-	8.5	15	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=16\text{V}$	-	1	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	3	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time <sup>2</sup>	$V_{\text{DS}}=15\text{V}$	-	5	-	ns
$t_{\text{r}}$	Rise Time	$I_{\text{D}}=1\text{A}$	-	9	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_{\text{G}}=3.3\Omega$	-	20	-	ns
$t_{\text{f}}$	Fall Time	$V_{\text{GS}}=5\text{V}$	-	5	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	400	1050	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	90	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	70	-	pF

### Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=1.2\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	1.2	V

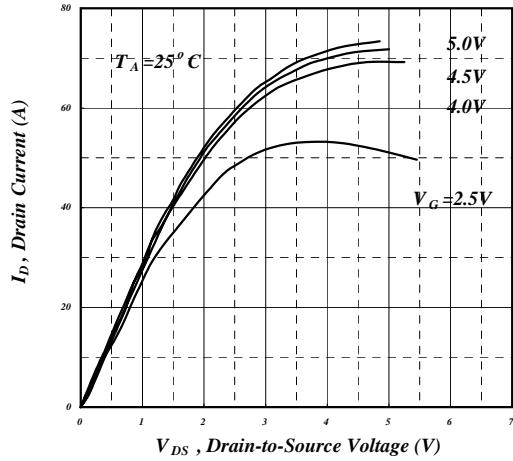
### Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board, t ≤ 10s ; 270°C/W when mounted on min. copper pad.

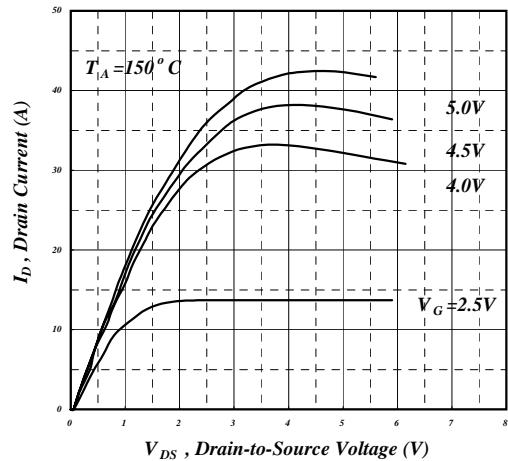
THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

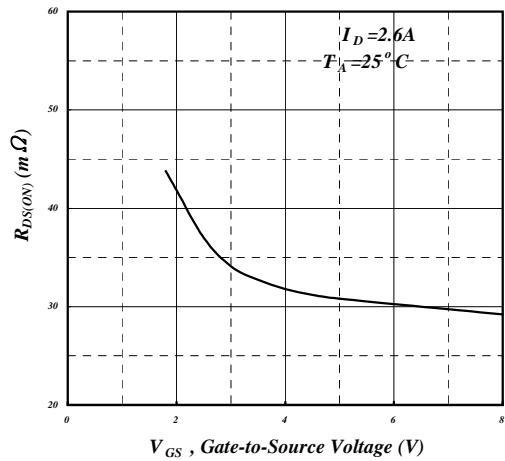
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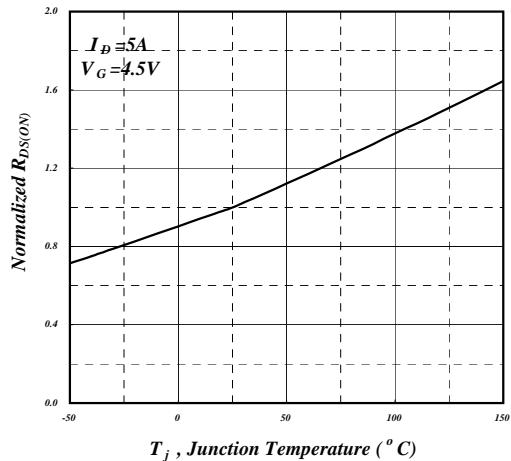
**Fig 1. Typical Output Characteristics**



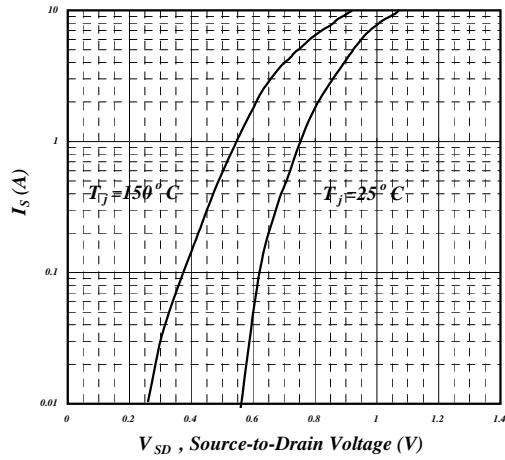
**Fig 2. Typical Output Characteristics**



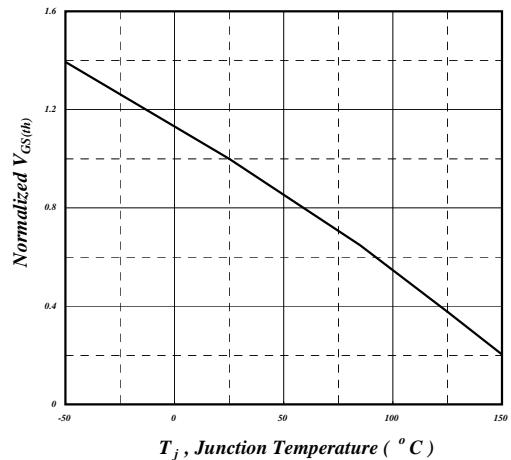
**Fig 3. On-Resistance v.s. Gate Voltage**



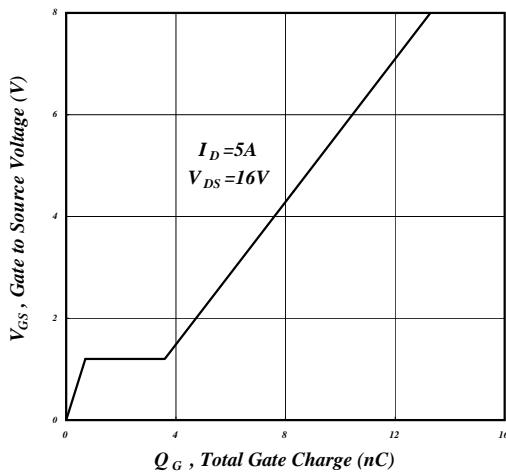
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



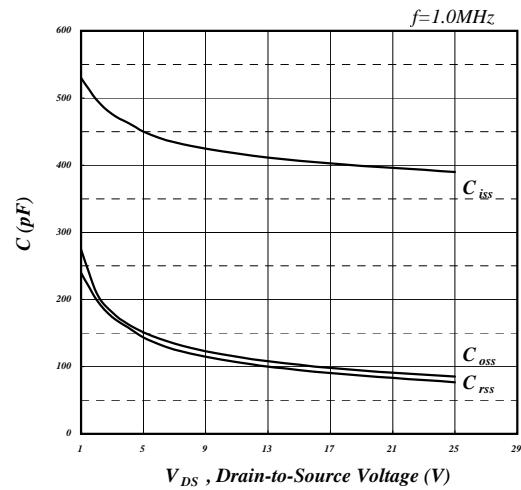
**Fig 5. Forward Characteristic of Reverse Diode**



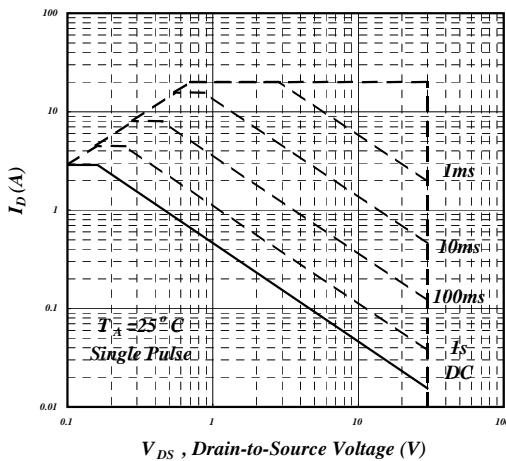
**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



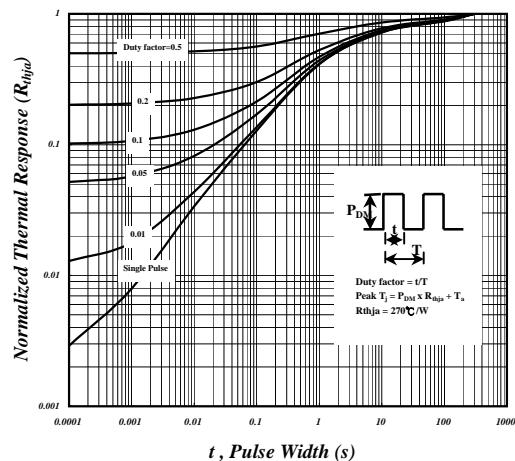
**Fig 7. Gate Charge Characteristics**



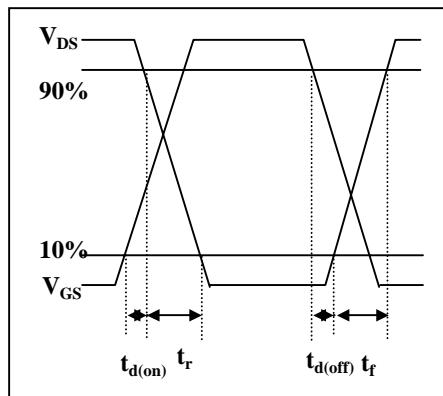
**Fig 8. Typical Capacitance Characteristics**



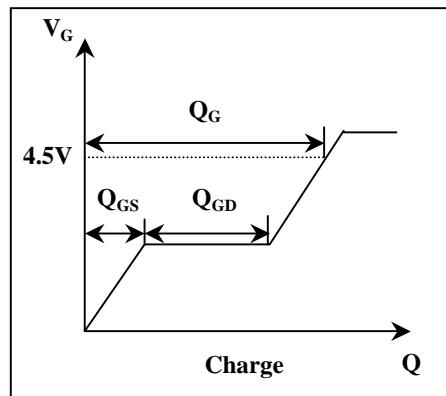
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Switching Time Waveform**



**Fig 12. Gate Charge Waveform**